

# N-channel enhancement mode vertical D-MOS transistor

BSN22

N AMER PHILIPS/DISCRETE 67E D

**FEATURES**

- Direct interface to C-MOS, TTL, etc.
- High-speed switching
- No secondary breakdown.

**QUICK REFERENCE DATA**

SYMBOL	PARAMETER	MAX.	UNIT
$V_{DS}$	drain-source voltage	50	V
$I_D$	DC drain current	100	mA
$R_{DS(on)}$	drain-source on-resistance	50	$\Omega$
$V_{GS(th)}$	gate-source threshold voltage	1.8	V

**DESCRIPTION**

N-channel enhancement mode vertical D-MOS transistor in a SOT23 envelope, intended for use as a surface-mounted device in general purpose small-signal fast switching applications.

**PINNING**

PIN	DESCRIPTION
Code: M18	
1	gate
2	source
3	drain

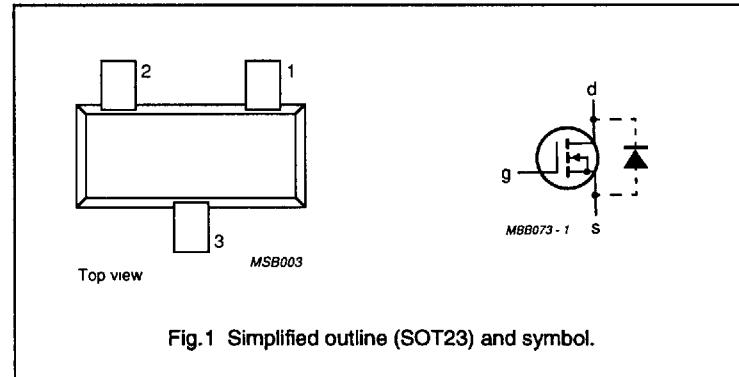


Fig.1 Simplified outline (SOT23) and symbol.

**LIMITING VALUES**

In accordance with the Absolute Maximum System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
$V_{DS}$	drain-source voltage		-	50	V
$\pm V_{GSO}$	gate-source voltage	open drain	-	20	V
$I_D$	DC drain current		-	100	mA
$I_{DM}$	peak drain current		-	300	mA
$P_{tot}$	total power dissipation	up to $T_{amb} = 25^\circ\text{C}$ (note 1)	-	250	mW
$T_{stg}$	storage temperature range		-65	150	$^\circ\text{C}$
$T_J$	junction temperature		-	150	$^\circ\text{C}$

**THERMAL RESISTANCE**

SYMBOL	PARAMETER	THERMAL RESISTANCE
$R_{th J-a}$	from junction to ambient (note 1)	500 K/W

**Note**

1. Transistor mounted on an FR-4 printboard.

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## CHARACTERISTICS

 $T_j = 25^\circ\text{C}$  unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{BRDSS}$	drain-source breakdown voltage	$I_D = 10 \mu\text{A}; V_{GS} = 0$	50	-	-	V
$I_{DS}$	drain-source leakage current	$V_{DS} = 40 \text{ V}; V_{GS} = 0$	-	-	1	$\mu\text{A}$
$\pm I_{GSS}$	gate-source leakage current	$\pm V_{GS} = 20 \text{ V}; V_{DS} = 0$	-	-	100	nA
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{GS} = V_{DS}$	0.4	-	1.8	V
$R_{DS(on)}$	drain-source on-resistance	$I_D = 100 \text{ mA}; V_{GS} = 10 \text{ V}$	-	12	20	$\Omega$
		$I_D = 100 \text{ mA}; V_{GS} = 5 \text{ V}$	-	20	30	$\Omega$
		$I_D = 10 \text{ mA}; V_{GS} = 2.5 \text{ V}$	-	30	50	$\Omega$
$ Y_{fs} $	transfer admittance	$I_D = 100 \text{ mA}; V_{DS} = 10 \text{ V}$	30	60	-	mS
$C_{iss}$	input capacitance	$V_{DS} = 10 \text{ V}; V_{GS} = 0; f = 1 \text{ MHz}$	-	6	10	pF
$C_{oss}$	output capacitance	$V_{DS} = 10 \text{ V}; V_{GS} = 0; f = 1 \text{ MHz}$	-	5	10	pF
$C_{rss}$	feedback capacitance	$V_{DS} = 10 \text{ V}; V_{GS} = 0; f = 1 \text{ MHz}$	-	1	3	pF
Switching times (see Figs 2 and 3)						
$t_{on}$	turn-on time	$I_D = 100 \text{ mA}; V_{DD} = 20 \text{ V}; V_{GS} = 0 \text{ to } 10 \text{ V}$	-	-	4	ns
$t_{off}$	turn-off time	$I_D = 100 \text{ mA}; V_{DD} = 50 \text{ V}; V_{GS} = 0 \text{ to } 10 \text{ V}$	-	-	8	ns

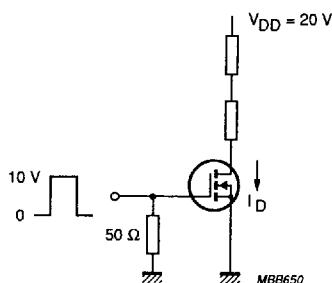


Fig.2 Switching times test circuit.

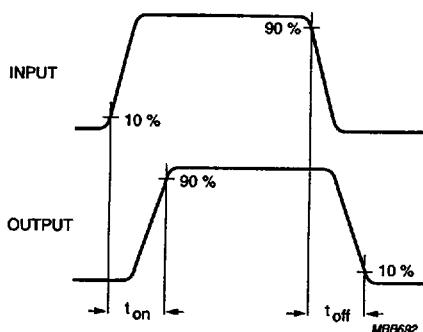


Fig.3 Input and output waveforms.